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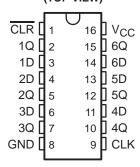
- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC}, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 2 V at V_{CC}, T_A = 25°C
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline (D, NS), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

description

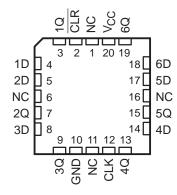
The 'LV174A devices are hex D-type flip-flops designed for 2-V to 5.5-V V_{CC} operation.

These devices are monolithic positive-edge-triggered flip-flops with a direct clear (CLR) input. Information at the data (D) inputs meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular voltage level and is not directly related to the

SN54LV174A . . . J OR W PACKAGE SN74LV174A . . . D, DB, DGV, NS, OR PW PACKAGE (TOP VIEW)



SN54LV174A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

transition time of the positive-going edge of the clock pulse. When the clock (CLK) input is at either the high or low level, the D-input signal has no effect at the output.

The SN54LV174A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LV174A is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

			1
	INPUTS		OUTPUT
CLR	CLK	D	Q
L	Х	Χ	L
Н	\uparrow	Н	Н
Н	\uparrow	L	L
Н	L	X	Q_0

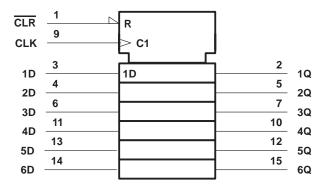


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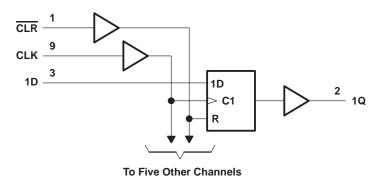


logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

logic diagram (positive logic)



Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (see Note 1)		–0.5 V to 7 V
Output voltage range, VO (see Notes 1 and 2)		$10.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$)		–20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CO}	c)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	- 	±25 mA
Continuous current through V _{CC} or GND		±50 mA
Package thermal impedance, θ _{JA} (see Note 3):	: D package	113°C/W
	DB package	131°C/W
	DGV package	180°C/W
	NS package	111°C/W
	PW package	149°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. This value is limited to 7 V maximum.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

			SN54L	V174A	SN74	LV174A	UNIT
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		2	5.5	2	5.5	V
		V _{CC} = 2 V	1.5		1.5		
VIH	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	$V_{CC} \times 0.$	7	VCC × 0	.7	V
VIH	r light-level lilput voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	VCC×0.	7	VCC × 0	.7	ľ
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	VCC×0.	7	VCC × 0	.7	
		V _{CC} = 2 V		0.5		0.5	
V _{IL}	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		$VCC \times 0.3$		$V_{CC} \times 0.3$	V
VIL	Low-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	ľ
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	
٧ _I	Input voltage		0	5.5	0	5.5	V
٧o	Output voltage		0	VCC	0	VCC	V
		V _{CC} = 2 V		– 50		- 50	μΑ
1011	High-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	Ć	- 2		-2	
ЮН	riigh-iever output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	200	-6		-6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	N. C.	-12		-12	
		V _{CC} = 2 V		50		50	μΑ
lOL	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		2	
I IOL	Low-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		6		6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12		12	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	200	0	200	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	0	100	0	100	ns/V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0	20	0	20	
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	,,	SN54LV174A	SN74LV174A	UNIT
PARAMETER	TEST CONDITIONS	vcc	MIN TYP MAX	MIN TYP MAX	UNIT
	I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} -0.1	V _{CC} -0.1	
Vou	$I_{OH} = -2 \text{ mA}$	2.3 V	2	2	V
VOH	I _{OH} = -6 mA	3 V	2.48	2.48	V
	I _{OH} = -12 mA	4.5 V	3.8	3.8	
	$I_{OL} = 50 \mu A$	2 V to 5.5 V	0.1	0.1	
VoL	$I_{OL} = 2 \text{ mA}$	2.3 V	0.4	0.4	V
VOL VOL	I _{OL} = 6 mA	3 V	0.44	0.44	V
	I _{OL} = 12 mA	4.5 V	0.55	0.55	
lį	V _I = V _{CC} or GND	5.5 V	±1	±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	20	μΑ
l _{off}	V_I or $V_O = 0$ to 5.5 V	0 V	5	5	μΑ
Ci	V _I = V _{CC} or GND	3.3 V	1.7	1.7	pF



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timing requirements over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

			T,	Δ = 25°C	;	SN54L	V174A	SN74L	/174A	UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT
	Pulse duration	CLR low	6			6.5		6.5		no
t _W	ruise duration	CLK high or low	7			7	$i_{\mathcal{U}}^{\mathcal{O}}_{U_{\mathcal{E}}}$	7		ns
	Oaten time hefere OLKA	Data	8.5			9.5	JIV	9.5		no
t _{su}	Setup time before CLK↑	CLR inactive	4			4	· ·	4		ns
t _h	Hold time, data after CLK↑		-0.5			0		0		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			T,	_A = 25°C	;	SN54L	/174A	SN74L	/174A	UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Γ.	Pulse duration	CLR low	5			5		5		no
t _W	ruise duration	CLK high or low	5			5	U.N	5		ns
	Out on the tare OUK	Data	5			6	JIL	6		no
t _{su}	Setup time before CLK↑	CLR inactive	3			3		3		ns
t _h	Hold time, data after CLK↑		0			0		0		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T,	ղ = 25°0	;	SN54L	V174A	SN74L\	/174A	UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	Pulse duration	CLR low	5			5		5		no
t _W	ruise duration	CLK high or low	5			5	$i_{\mathcal{U}}^{\mathcal{O}}_{U_{\mathcal{E}}}$	5		ns
	Oaton Carabatana OLIKA	Data	4.5			4.5	JIV	4.5		20
t _{su}	Setup time before CLK↑	CLR inactive	2.5			2.5	Y	2.5		ns
t _h	Hold time, data after CLK↑		0.5			0.5		0.5		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

• •											
PARAMETER	FROM	то	LOAD	T,	4 = 25°C	;	SN54L	/174A	SN74L\	/174A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
f			C _L = 15 pF*	55	115		50		50		MHz
^f max			C _L = 50 pF	45	90		40	,C),	40		IVITIZ
t.,*	CLR	Q	C: - 15 pE		6.3	17.3	-30	19.5	1	19.5	ns
^t pd*	CLK		C _L = 15 pF		8.4	17.1	()	19	1	19	113
	CLR	Q			8.2	21.9	1	23.5	1	23.5	
^t pd	CLK] ~	$C_{L} = 50 pF$		10.8	20.6	1	23	1	23	ns
t _{sk(o)} †]			2				2	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



[†] Skew between any two outputs of the same package switching in the same direction

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	4 = 25°C	;	SN54L	V174A	SN74L\	/174A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF*	95	170		80		80		MHz
fmax			C _L = 50 pF	55	130		50	,C),	50		IVITIZ
t*	CLR	Q	C: _ 15 pE		4.5	11.4	.35	13.5	1	13.5	ns
tpd*	CLK	Q	C _L = 15 pF		5.8	11	(h	13	1	13	115
	CLR	Q			6	14.9	1	17	1	17	
^t pd	CLK	Q	C _L = 50 pF		7.5	14.5	1	16.5	1	16.5	ns
t _{sk(o)} †						1.5				1.5	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	<u> </u> = 25°C	;	SN54L	V174A	SN74L\	/174A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
f			C _L = 15 pF*	130	240		110		110		MHz
f _{max}			C _L = 50 pF	90	180		80	,C),	80		IVIIIZ
t1*	CLR	Q	C: - 15 pF		3	7.6	.89	9	1	9	ns
tpd*	CLK	Q	C _L = 15 pF		4.1	7.2	6,4	8.5	1	8.5	113
+ .	CLR	Q			4.2	9.6	1	11	1	11	
^t pd	CLK	Q	C _L = 50 pF		5.5	9.2	1	10.5	1	10.5	ns
t _{sk(o)} †						1				1	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, $V_{CC} = 3.3 \text{ V}$, $C_L = 50 \text{ pF}$, $T_A = 25^{\circ}\text{C}$ (see Note 5)

	PARAMETER	SN	74LV174	Α	UNIT
	FARAWIE I ER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.34	0.8	V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.3	-0.8	V
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		3.02		V
V _{IH(D)}	High-level dynamic input voltage	2.31			V
V _{IL(D)}	Low-level dynamic input voltage			0.99	V

NOTE 5: Characteristics are for surface-mount packages only.

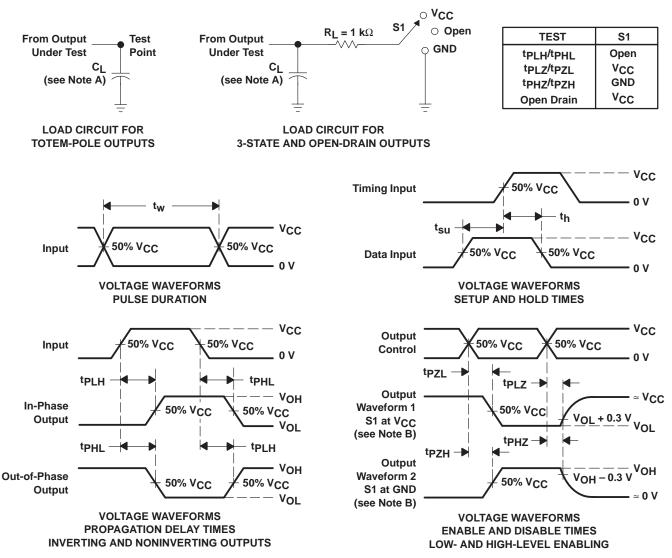
operating characteristics, T_A = 25°C

	PARAMETER	TEST CONDITIONS	v _{CC}	TYP	UNIT
C	Power dissipation capacitance	C ₁ = 50 pF, f = 10 MHz	3.3 V	14	pF
Cpd	i ower dissipation capacitance	CL = 50 pr, T = 10 MHZ	5 V	15.1	ρι

[†] Skew between any two outputs of the same package switching in the same direction

[†] Skew between any two outputs of the same package switching in the same direction

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C₁ includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tpLz and tpHz are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpHL and tpLH are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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